

Notice of References Cited

Application/Control No.

10/770,651

Applicant(s)/Patent Under
Reexamination
DIETRICH, FRANK

Examiner

Anjan K. Deb

Art Unit

2858

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,292,615 A	09-1981	Ohashi, Shigeo	335/205
*	B	US-4,581,525 A	04-1986	Horstmann, Frank R.	235/493
*	C	US-4,644,101 A	02-1987	Jin et al.	178/18.05
*	D	US-5,169,471 A	12-1992	Strasser, Gene W.	156/272.4
*	E	US-5,429,701 A	07-1995	Lu, Neng-Hsing	156/272.4
*	F	US-5,522,962 A	06-1996	Koskenmaki et al.	156/272.4
*	G	US-2004/0074569 A1	04-2004	Arai et al.	148/302
*	H	US-2006/0273785 A1	12-2006	Lindblom et al.	324/244
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 04028203 A	01-1992	Japan	TANABE, KOJI	H01C 10/00
	O	FR 1468702 A	02-1967	FR	Knapp-Ziller	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.